

Search Notes**Application/Control No.**

10/570,904

Examiner

YONG D. PAK

**Applicant(s)/Patent under
Reexamination**

TAKESHIMA ET AL.

Art Unit

1652

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
435	190	9/23/2008	YP
435	440	9/23/2008	YP
536	23.2	9/23/2008	YP
stic: seq id no.1		9/23/2008	YP

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
stic: seq id no:1, see score	9/23/2008	YP
east (all databases): text and inventor search	9/23/2008	YP
PALM: inventor search	9/23/2008	YP